

# Production Line Control in Semiconductor High-Volume Manufacturing

JMP Discovery Summit - Munich 2020

Stéphane ASTIE - Yield Manager

Guillaume BUGNON - Data Engineer



soitec



# Agenda

**1** SOITEC who we are

**2** Problem statement

**3** Data & Methodology

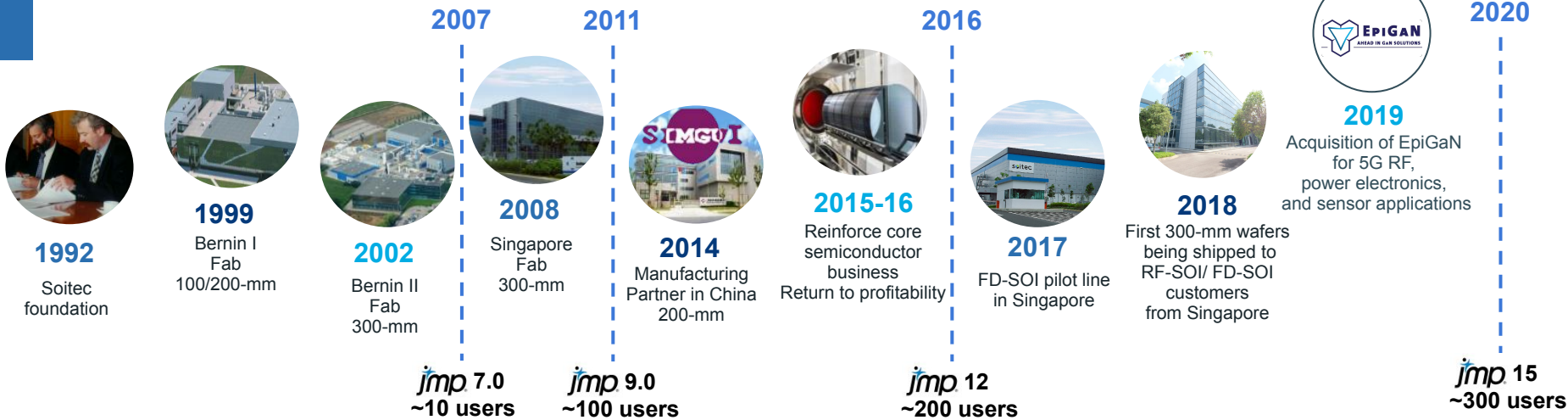
**4** JMP demo

**5** Conclusion

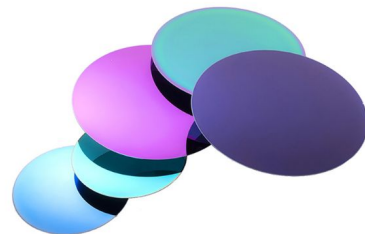
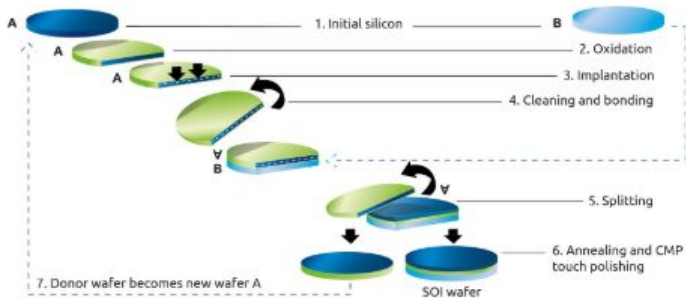


# 1 SOITEC who we are

# Soitec at a glance



## Smart Cut™



# Soitec – Today

## DESIGNER & MANUFACTURER OF INNOVATIVE SEMICONDUCTOR MATERIALS



1

**Largest manufacturer of engineered substrates**  
LEADER

2

**Unique technologies**  
SMART CUT™, SMART STACKING

4

**High-growth markets**  
SMARTPHONES, AUTOMOTIVE, CLOUD & INFRASTRUCTURE, IOT

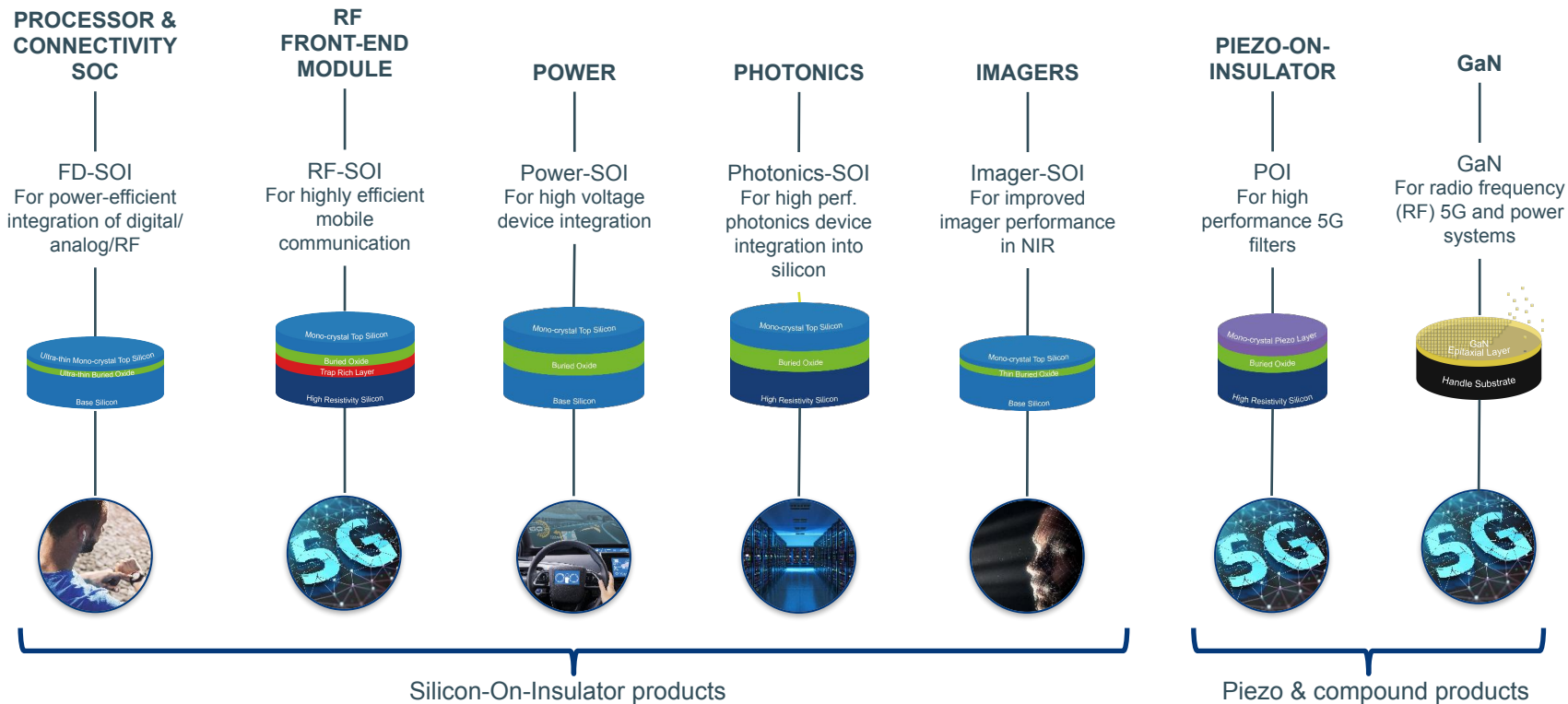
6

**Wafer fabs (150, 200 & 300 mm)**  
FRANCE, BELGIUM, SINGAPORE, CHINA\*  
\* Partnership with Shanghai Simgui Technology Co. Ltd. (Simgui)

1,450

**Employees Worldwide**  
GLOBAL PRESENCE

# A broad product portfolio of engineered substrates



# A global multi-site industrial footprint



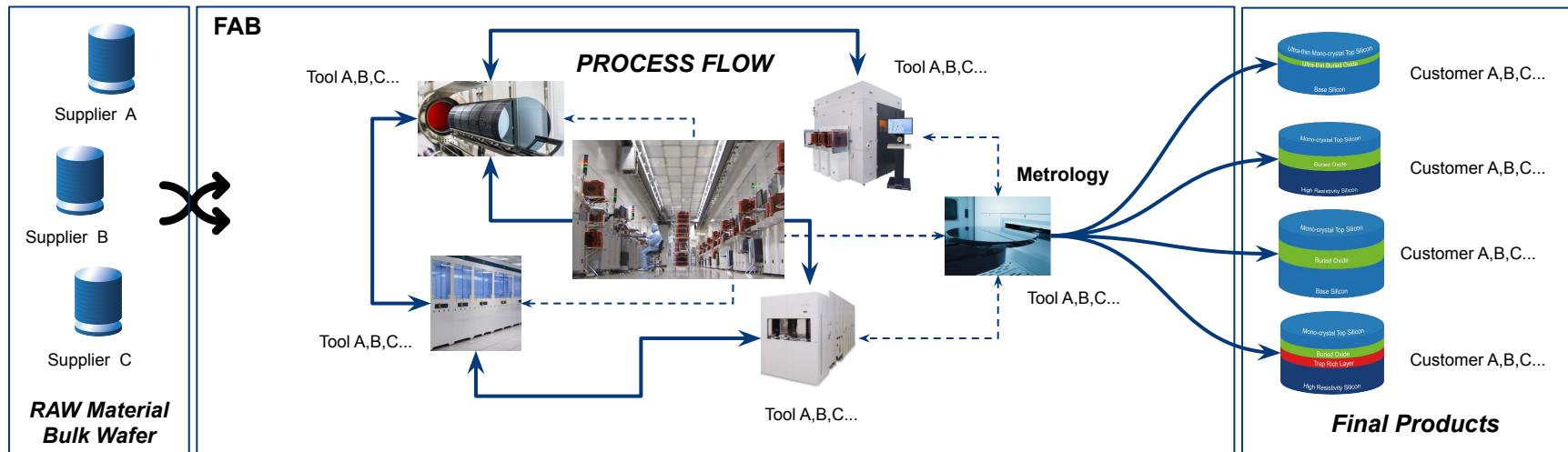


## 2 Problem statement



# Yield drift detection in a full fab environment

Data quality and real time analysis are key to minimize scrap, reduce wafer cost and quality impacts



- Multiple Raw Materials suppliers
- Same tools can be used at different process stages
- New tools, new stages, new processes
- Multiple products and customers specifications
- Several Yield engineers & JSL scripts
- Data everywhere (incoming, in line, end of line)



**Common interface for all Yield engineers**  
**Data uploaded automatically real time**  
**Trends, Analysis by Products**



3

# DATA & METHODOLOGY

# Some... data

- › Database size : **3.7TB**
- › **Each day**, lot of data are collected into different databases systems
  - › **> 2 000 000** wafer measurements
  - › **> 1 000 000** equipment measurements
- › To analyze all these data, Eng. need to have a quick and easy access to them
  - › **SOLUTION : publish “Ready To Use” data tables**

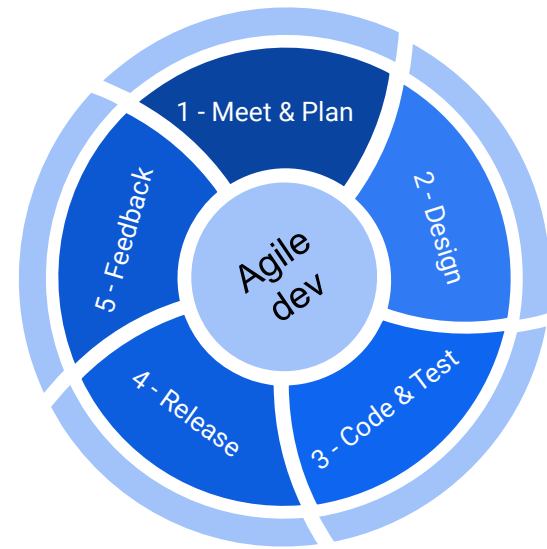


# Methodology

- › “Ready To Use” tables can help to
  - › Prevent drift detection
  - › find root-cause issue
  - › root causes could be due to materials, equipment...

- › **Agile approach**

- › Combined work with Yield team to define relevant data
- › and **iterative approach**
  - Equipment historical data (eqpt name / in-out date...)
  - Process parameters (product measurement)
  - Tests parameters
  - Material parameters
- › Add more or different data and data sources at each sprint



## 4 JMP demo



5

# Conclusion

# Conclusion

- › Data are “Ready To Use” and easy to access
  - › Data available automatically for new products / process / tools
  - › Standardization << All data tables have same format
  - › Yield engineers backup periods, training easier
  - › Soitec JMP users data analysis sharing improved
- 
- › JMP facilitates database access : easy to request Data Lake or multiple db sources
  - › JMP can handle lot of data and users can visualize all of them
  - › JMP is a part of Soitec Industrie 4.0 program

# Thank you

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